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CD4011B, CD4012B, CD4023B Types

CMOS NAND GATES

High-Voltage Types (20-Volt Rating)

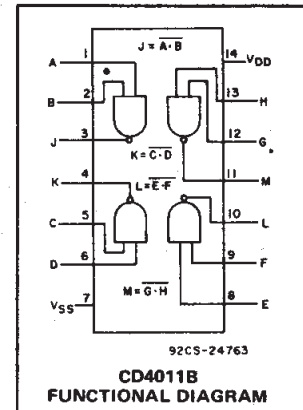
- Quad 2 Input – CD4011B
- Dual 4 Input – CD4012B
- Triple 3 Input – CD4023B

■ CD4011B, CD4012B, and CD4023B NAND gates provide the system designer with direct implementation of the NAND function and supplement the existing family of CMOS gates. All inputs and outputs are buffered.

The CD4011B, CD4012B, and CD4023B types are supplied in 14-lead hermetic dual-in-line ceramic packages (D and F suffixes), 14-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).

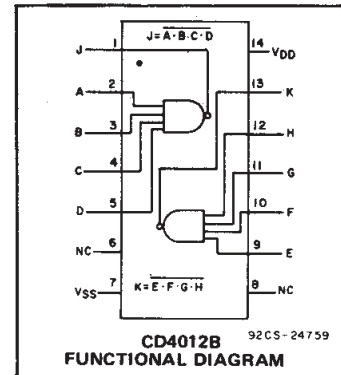
Features:

- Propagation delay time = 60 ns (typ.) at $C_L = 50$ pF, $V_{DD} = 10$ V
- Buffered inputs and outputs
- Standardized symmetrical output characteristics
- Maximum input current of $1 \mu A$ at 18 V over full package temperature range; 100 nA at 18 V and 25°C
- 100% tested for quiescent current at 20 V
- 5-V, 10-V, and 15-V parametric ratings
- Noise margin (over full package temperature range):
 - 1 V at $V_{DD} = 5$ V
 - 2 V at $V_{DD} = 10$ V
 - 2.5 V at $V_{DD} = 15$ V
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of "B" Series CMOS Devices"



MAXIMUM RATINGS, Absolute-Maximum Values:

| | | |
|--|--|---------------------------------|
| DC SUPPLY-VOLTAGE RANGE, (V_{DD}) | | |
| Voltages referenced to V_{SS} Terminal | | -0.5V to +20V |
| INPUT VOLTAGE RANGE, ALL INPUTS | | -0.5V to $V_{DD} + 0.5V$ |
| DC INPUT CURRENT, ANY ONE INPUT | | ± 10 mA |
| POWER DISSIPATION PER PACKAGE (P_D): | | |
| For $T_A = -55^\circ C$ to $+100^\circ C$ | | 500mW |
| For $T_A = +100^\circ C$ to $+125^\circ C$ | Derate Linearly at 12mW/ $^\circ C$ to 200mW | |
| DEVICE DISSIPATION PER OUTPUT TRANSISTOR | | |
| FOR $T_A =$ FULL PACKAGE-TEMPERATURE RANGE (All Package Types) | | 100mW |
| OPERATING-TEMPERATURE RANGE (T_A) | | $-55^\circ C$ to $+125^\circ C$ |
| STORAGE TEMPERATURE RANGE (T_{stg}) | | $-65^\circ C$ to $+150^\circ C$ |
| LEAD TEMPERATURE (DURING SOLDERING): | | |
| At distance $1/16 \pm 1/32$ inch (1.59 ± 0.79 mm) from case for 10s max | | $+265^\circ C$ |

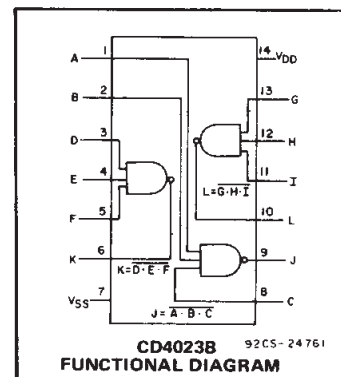
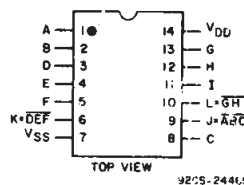
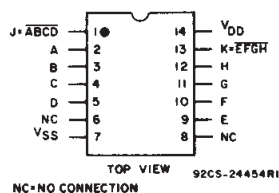
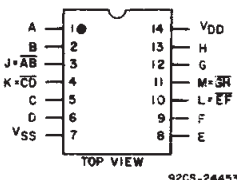


RECOMMENDED OPERATING CONDITIONS

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

| CHARACTERISTIC | LIMITS | | UNITS |
|---|--------|------|-------|
| | MIN. | MAX. | |
| Supply-Voltage Range (For $T_A =$ Full Package Temperature Range) | 3 | 18 | V |

TERMINAL ASSIGNMENTS



CD4011B, CD4012B, CD4023B Types

STATIC ELECTRICAL CHARACTERISTICS

| CHARACTERISTIC | CONDITIONS | | | LIMITS AT INDICATED TEMPERATURES (°C) | | | | | | | UNITS |
|--|--------------------|---------------------|---------------------|---------------------------------------|-------|-------|-------|-------|-------------------|------|-------|
| | V _O (V) | V _{IN} (V) | V _{DD} (V) | -55 | -40 | +85 | +125 | +25 | | | |
| | | | | | | | | Min. | Typ. | Max. | |
| Quiescent Device Current, I _{DD} Max. | - | 0,5 | 5 | 0.25 | 0.25 | 7.5 | 7.5 | - | 0.01 | 0.25 | μA |
| | - | 0,10 | 10 | 0.5 | 0.5 | 15 | 15 | - | 0.01 | 0.5 | |
| | - | 0,15 | 15 | 1 | 1 | 30 | 30 | - | 0.01 | 1 | |
| | - | 0,20 | 20 | 5 | 5 | 150 | 150 | - | 0.02 | 5 | |
| Output Low (Sink) Current I _{OL} Min. | 0.4 | 0,5 | 5 | 0.64 | 0.61 | 0.42 | 0.36 | 0.51 | 1 | - | mA |
| | 0.5 | 0,10 | 10 | 1.6 | 1.5 | 1.1 | 0.9 | 1.3 | 2.6 | - | |
| | 1.5 | 0,15 | 15 | 4.2 | 4 | 2.8 | 2.4 | 3.4 | 6.8 | - | |
| Output High (Source) Current, I _{OH} Min. | 4.6 | 0,5 | 5 | -0.64 | -0.61 | -0.42 | -0.36 | -0.51 | -1 | - | mA |
| | 2.5 | 0,5 | 5 | -2 | -1.8 | -1.3 | -1.15 | -1.6 | -3.2 | - | |
| | 9.5 | 0,10 | 10 | -1.6 | -1.5 | -1.1 | -0.9 | -1.3 | -2.6 | - | |
| | 13.5 | 0,15 | 15 | -4.2 | -4 | -2.8 | -2.4 | -3.4 | -6.8 | - | |
| Output Voltage: Low-Level, V _{OL} Max. | - | 0,5 | 5 | 0.05 | | | | - | 0 | 0.05 | V |
| | - | 0,10 | 10 | 0.05 | | | | - | 0 | 0.05 | |
| | - | 0,15 | 15 | 0.05 | | | | - | 0 | 0.05 | |
| Output Voltage: High-Level, V _{OH} Min. | - | 0,5 | 5 | 4.95 | | | | 4.95 | 5 | - | V |
| | - | 0,10 | 10 | 9.95 | | | | 9.95 | 10 | - | |
| | - | 0,15 | 15 | 14.95 | | | | 14.95 | 15 | - | |
| Input Low Voltage, V _{IL} Max. | 4.5 | - | 5 | 1.5 | | | | - | - | 1.5 | V |
| | 9 | - | 10 | 3 | | | | - | - | 3 | |
| | 13.5 | - | 15 | 4 | | | | - | - | 4 | |
| Input High Voltage, V _{IH} Min. | 0.5, 4.5 | - | 5 | 3.5 | | | | 3.5 | - | - | V |
| | 1, 9 | - | 10 | 7 | | | | 7 | - | - | |
| Input Current I _{IN} Max. | | 0,18 | 18 | ±0.1 | ±0.1 | ±1 | ±1 | - | ±10 ⁻⁵ | ±0.1 | μA |

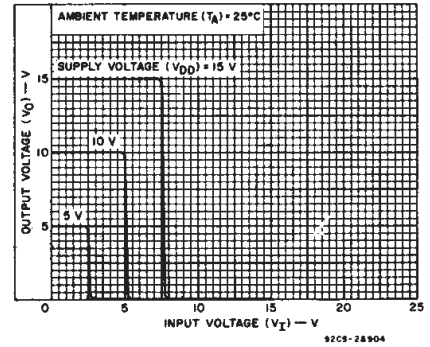


Fig. 1 - Typical voltage transfer characteristics.

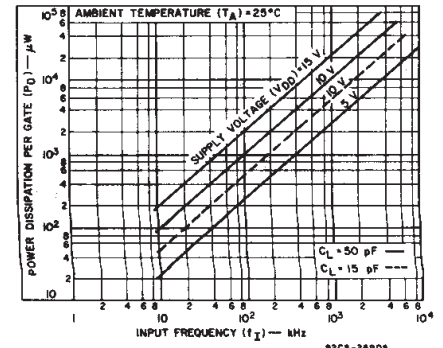


Fig. 2 - Typical power dissipation characteristics.

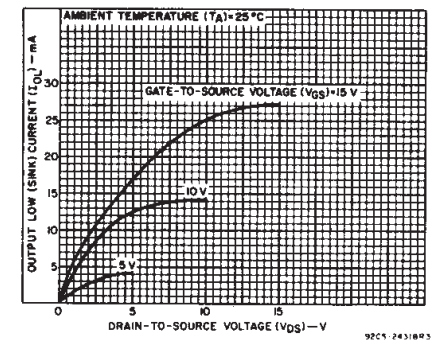


Fig. 3 - Typical output low (sink) current characteristics.

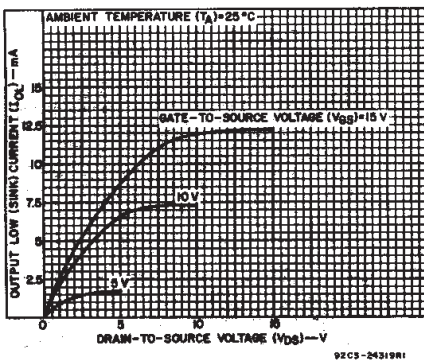


Fig. 4 - Minimum output low (sink) current characteristics.

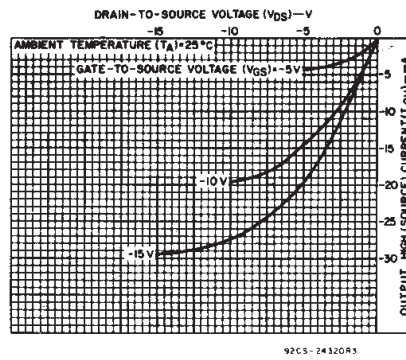


Fig. 5 - Typical output high (source) current characteristics.

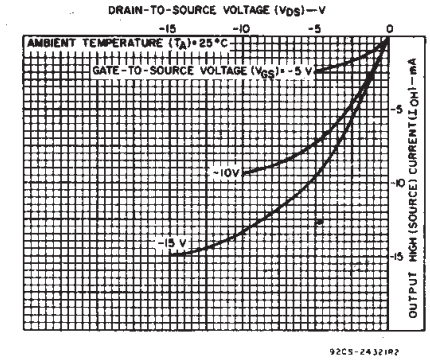
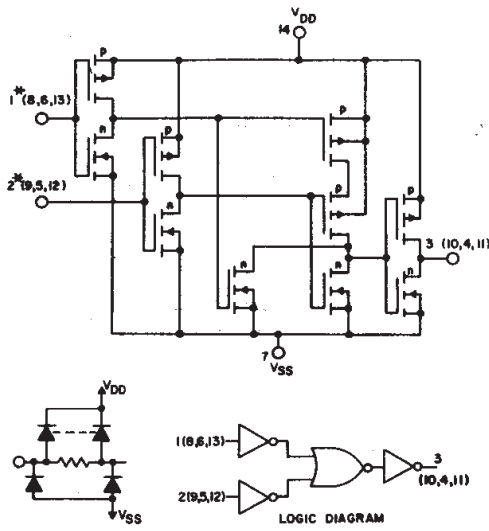


Fig. 6 - Minimum output high (source) current characteristics.

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HIGH VOLTAGE ICs

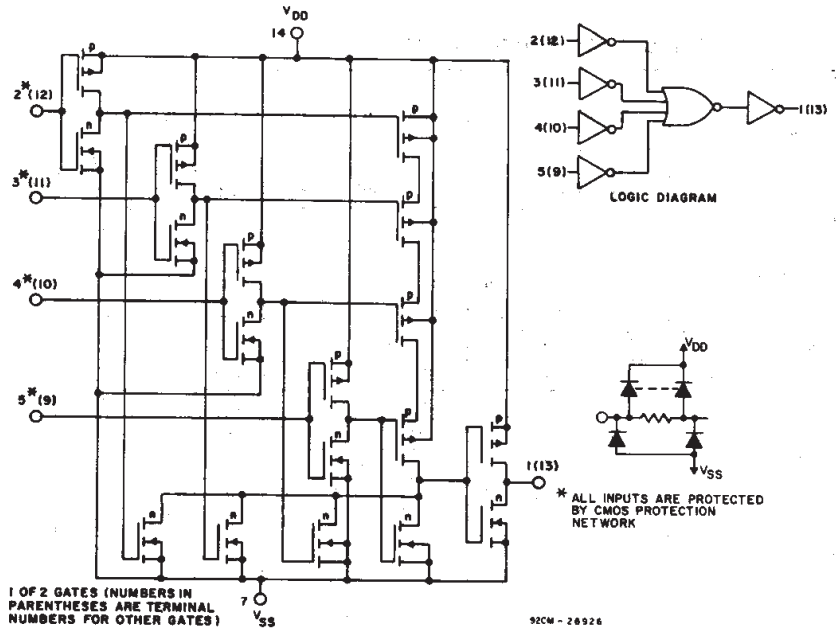
CD4011B, CD4012B, CD4023B Types



* ALL INPUTS ARE PROTECTED BY CMOS PROTECTION NETWORK

1 OF 4 GATES (NUMBERS IN PARENTHESES ARE TERMINAL NUMBERS FOR OTHER GATES)

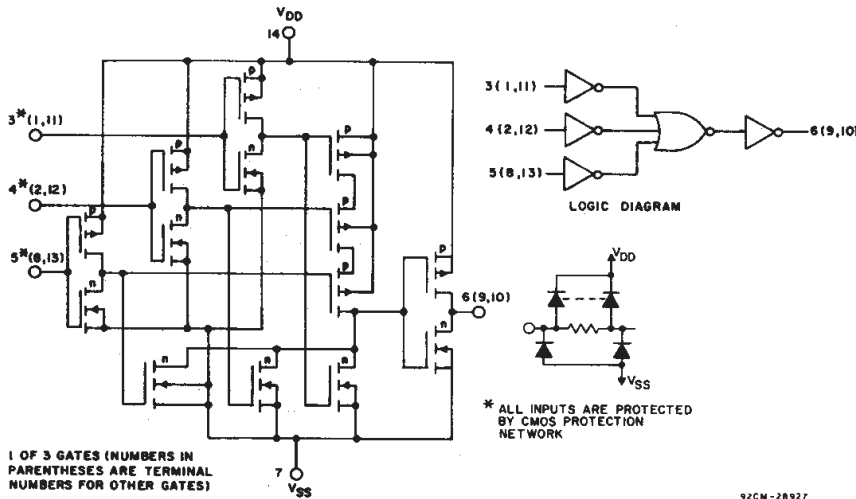
Fig.7 - Schematic and logic diagrams for CD4011B.



1 OF 2 GATES (NUMBERS IN PARENTHESES ARE TERMINAL NUMBERS FOR OTHER GATES)

92CM-28926

Fig.8 - Schematic and logic diagrams for CD4012B.



1 OF 3 GATES (NUMBERS IN PARENTHESES ARE TERMINAL NUMBERS FOR OTHER GATES)

* ALL INPUTS ARE PROTECTED BY CMOS PROTECTION NETWORK

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Fig. 9 - Schematic and logic diagrams for CD4023B.

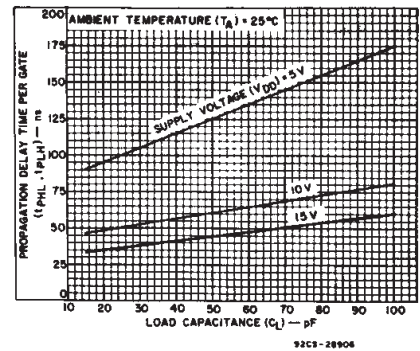


Fig.10 - Typical propagation delay time per gate as a function of load capacitance.

DYNAMIC ELECTRICAL CHARACTERISTICS

At $T_A = 25^\circ\text{C}$; Input $t_r, t_f = 20\text{ ns}$, $C_L = 50\text{ pF}$, $R_L = 200\text{ k}\Omega$

| CHARACTERISTIC | TEST CONDITIONS | LIMITS | | UNITS | |
|--|-----------------|-----------------------|------|-------|------|
| | | V _{DD} VOLTS | TYP. | | MAX. |
| Propagation Delay Time, t_{PHL}, t_{PLH} | | 5 | 125 | 250 | ns |
| | | 10 | 60 | 120 | |
| | | 15 | 45 | 90 | |
| Transition Time, t_{THL}, t_{TLH} | | 5 | 100 | 200 | ns |
| | | 10 | 50 | 100 | |
| | | 15 | 40 | 80 | |
| Input Capacitance, C_{iN} | Any Input | | 5 | 7.5 | pF |

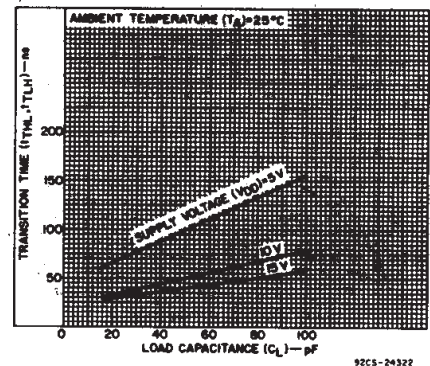


Fig.11 - Typical transition time as a function of load capacitance.

CD4011B, CD4012B, CD4023B Types

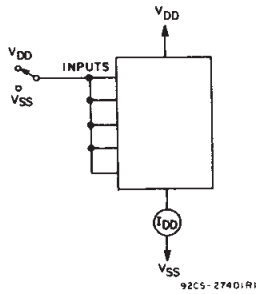


Fig. 12 - Quiescent-device-current test circuit.

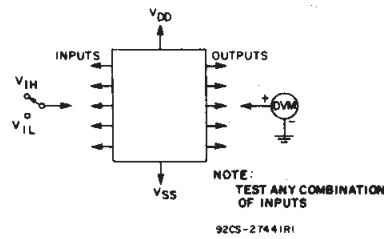


Fig. 13 - Input-voltage test circuit.

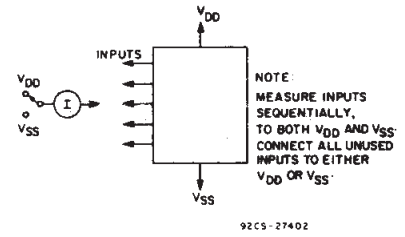
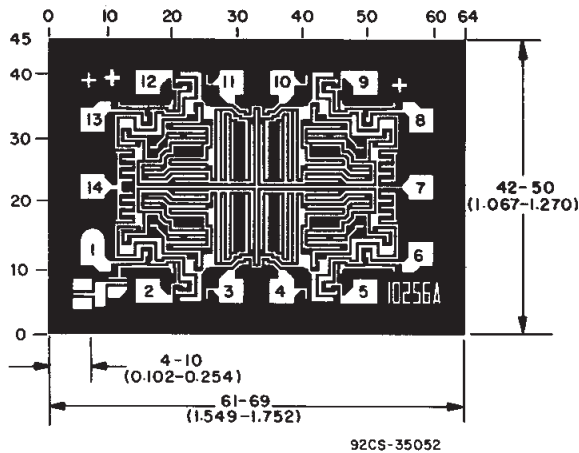
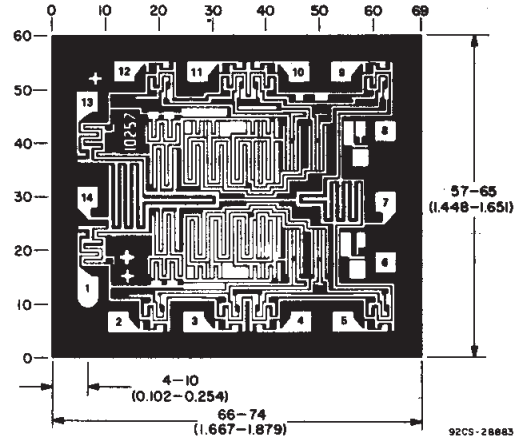


Fig. 14 - Input-current test circuit.

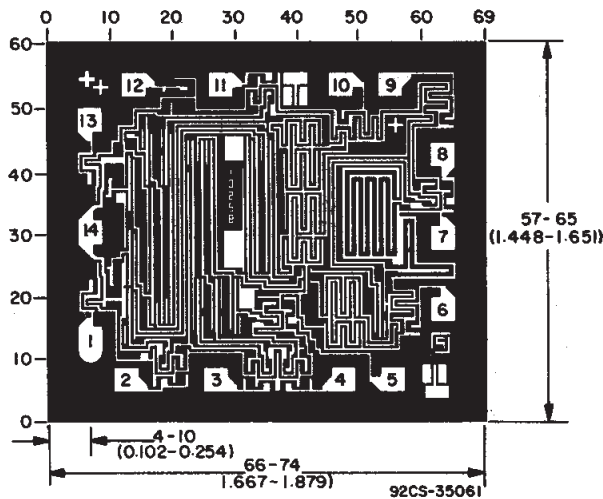
Chip Dimensions and Pad Layouts



CD4011BH



CD4012BH



CD4023BH

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

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HIGH VOLTAGE ICs

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